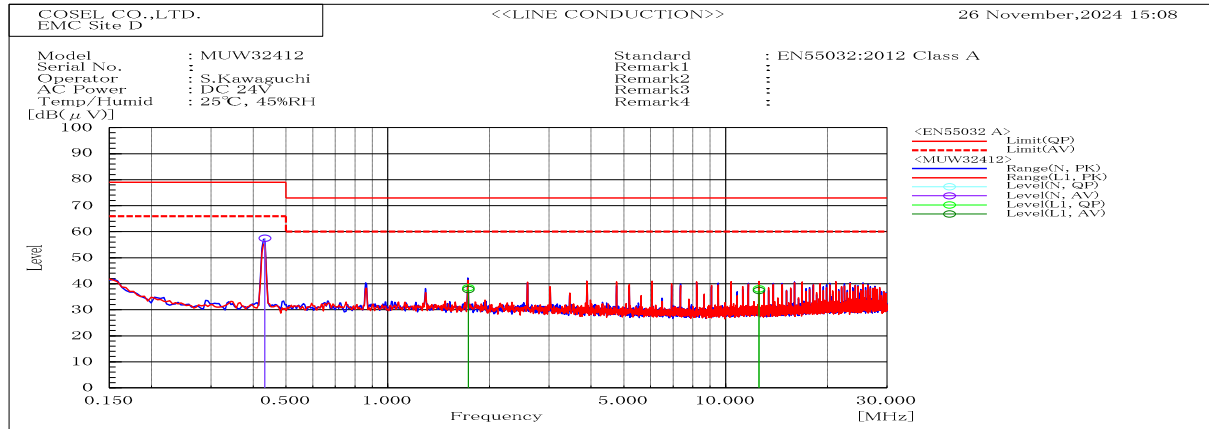
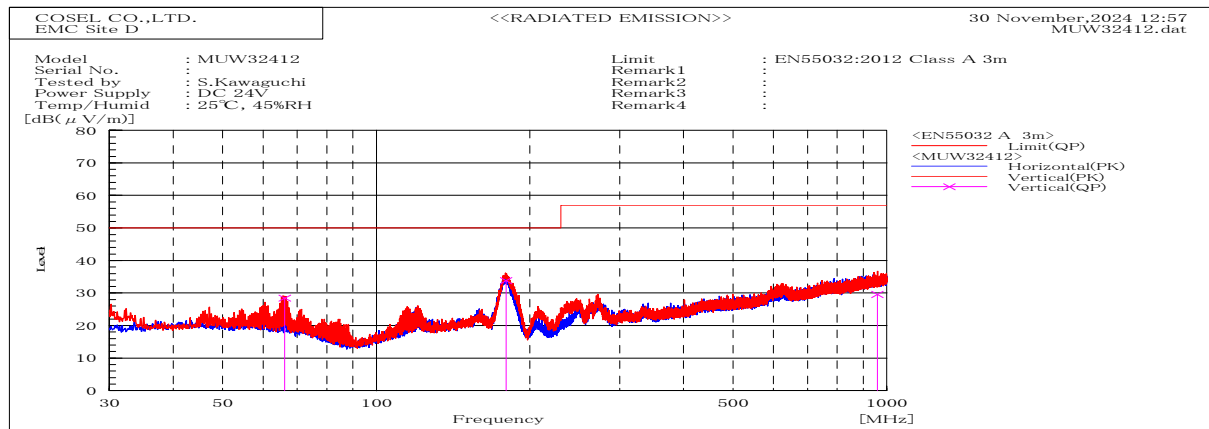


DATA SHEET

Model		MUW32412	Date	30-Nov-24
Test		EMI Line conduction & Radiated emission	Temp.	25 degreeC
			Humid.	45 %RH
			Tested by	S.Kawaguchi



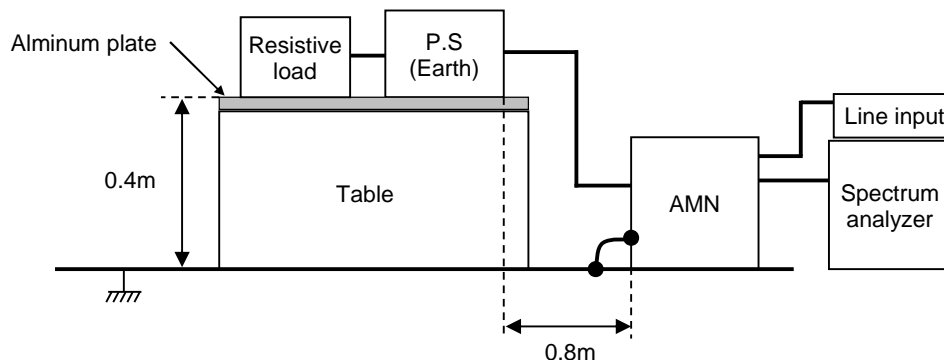
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
1.731	L1	38.5	37.8	73	60	34.5	22.2	Pass	
12.556	L1	38	37.4	73	60	35	22.6	Pass	
0.433	N	57.6	57.5	79	66	21.4	8.5	Pass	



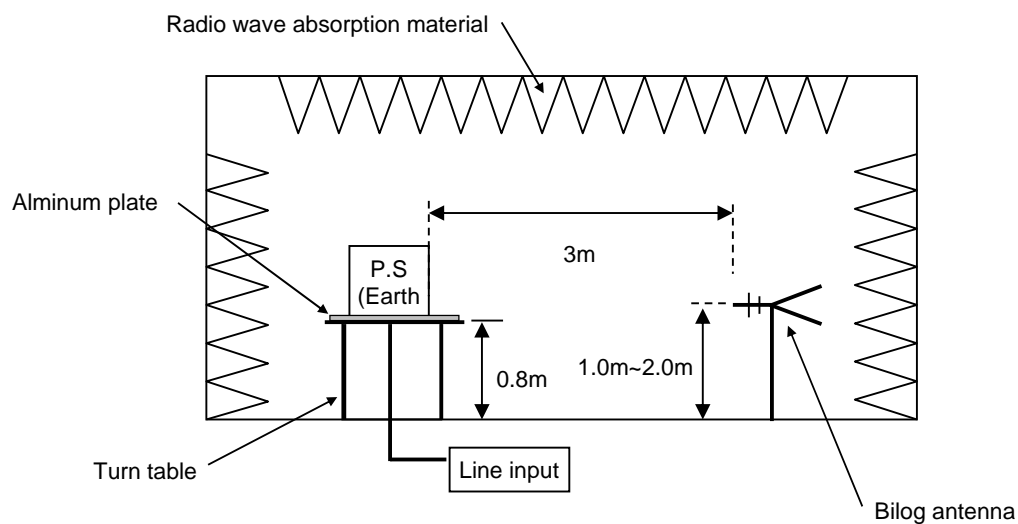
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP					
179.57	V	Stable	33.8	50	16.2	Pass	100.2	34.8	
66.164	V	Stable	28.4	50	21.6	Pass	100.2	274.3	
958.741	V	Stable	29.6	57	27.4	Pass	140.7	289.1	

DATA SHEET		Date	30-Nov-24
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

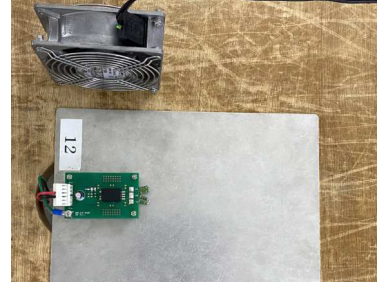
Test : EMI
Model Name: MUW3□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

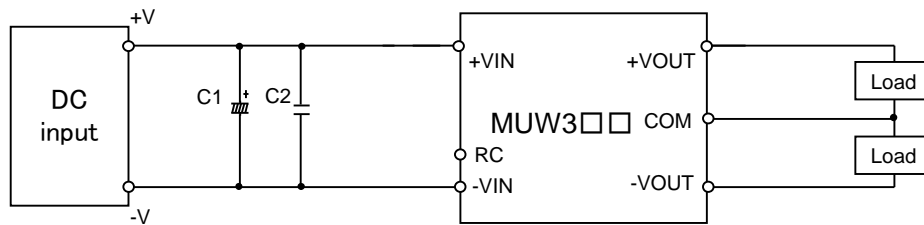


Fig.1 MUW305□, MUW312□, MUW324□ Testing circuitry

- | | | | |
|------|---------|-----------------|---|
| C1 : | MUW305□ | 16V 220 μ F | Electric capacitor (UPWseries NICHICON) |
| | MUW312□ | 50V 100 μ F | Electric capacitor (UPWseries NICHICON) |
| | MUW324□ | - | |
| C2 : | MUW305□ | 16V 22 μ F | Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING) |
| | MUW312□ | 25V 22 μ F | Ceramic capacitor (C3216JB1E226MT TDK) |
| | MUW324□ | 50V 10 μ F | Ceramic capacitor (C3216X7R1H106KT TDK) |

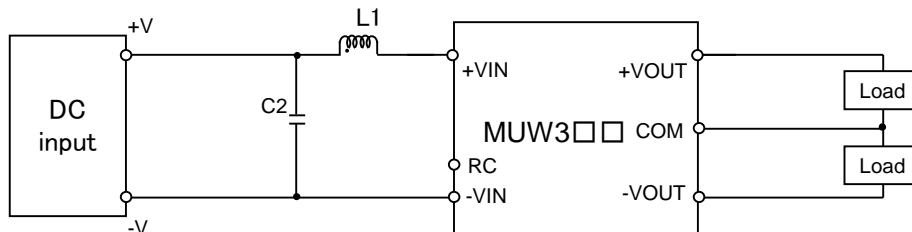


Fig.2 MUW348□ Testing circuitry

- | | | | |
|------|---------|------------------|--|
| C2 : | MUW348□ | 100V 2.2 μ F | Ceramic capacitor (C3216X7S2A225KT TDK) |
| L1 : | MUW348□ | 520mA 15 μ H | Inductor (LQH32PN150MN0L MURATA MANUFACTURING) |